Fault Tolerant Computing

CS 530

Software Reliability: Static Factors

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Wholistic Engineering for Software Reliability

Outline

• Techniques available in Software Reliability
• Software & Hardware Reliability
• Defect density & factors that control it
  • Phase
  • Programming team and process maturity
  • Software Structure
  • Requirement volatility
Time to go Wholistic

- We have data on different aspects of reliability to have reasonable hypotheses.
- We know limitations of the hypotheses.
- We have enough techniques & tools to start engineering.
- Accuracy **comparable or better** than established hardware reliability methods.

Why It’s Needed Now

- Reliability expectations growing fast
- Large projects, little time
- Quick changes in developing environments
- Reliance on a single technique not enough
- Pioneering work has already been done.
Why It’s Time: Emergence of SRE

- **Craft**: incremental intuitive refinement
- **Science**: *why* it is so
  - Observe, hypothesize, assess accuracy
- **Engineering**: *how* to get what we want
  - Approximate, integrate, evaluate
- Are we ready to engineer software reliability?

Learning from Hardware Reliability

- Hardware Reliability Methods: Well known, well established methods
  - Now standard practice
  - Used by government and industrial organizations worldwide
  - Considered a *well established science*
Hardware Reliability: The Status (1)

- Earliest tube computers: MTTF comparable to some computation times!
- 1956 RCA TR-1100: component failure rate models
- 1959: MIL-HDBK-217A: common failure rate: $0.4 \times 10^{-6}$ for all ICs for all cases
- Revised about every 7 years

Hardware Reliability: The Status (2)

- Why use hardware reliability prediction?
  - Feasibility Study: initial design
  - Compare Design Alternatives: Reliability along with performance and cost
  - Find Likely Problem Spots - high contributors to the product failure rate
  - Track Reliability Improvements
Hardware vs Software Faults

- Hardware faults are generally field or manufacturing process defects.
- Software faults are due to incorrect design/implementation ("man-made").
- During debugging, bugs are removed thus reliability grows.
- Design defects on hardware are basically similar to software defects.

Hardware vs Software Reliability Methods: Use of models

<table>
<thead>
<tr>
<th></th>
<th>Model selection based on</th>
<th>Parameters estimated using</th>
</tr>
</thead>
<tbody>
<tr>
<td>Hardware</td>
<td>Past experience with similar units</td>
<td>Past experience with similar units</td>
</tr>
</tbody>
</table>
| Software | Past experience* with similar units | Early: past experience with similar units  
|          |                           | Later: from the unit under test |

* Some researchers have suggested model selected using early test data from the software under test.
Basic Definitions

- **Defect**: requires a corrective action
- **Defect density**: defects per 1000 non-comment source lines (NC LOC).
- **Failure intensity**: rate at which failures are encountered during execution.
- **MTTF** (mean time to failure): inverse of failure intensity.

In this case mean is not taken over time, rather it is an ensemble average.

Basic Definitions (2)

- **Reliability**
  - \( R(t) = p\{\text{no failures in time (0,t)} \} \)
- **Transaction reliability**: probability that a single transaction will be executed correctly.
- **Test Time**: may be measures in **CPU time** or some measure of **testing effort**.
Why is Defect Density Important?

- Important measurement of reliability
- Often used as release criteria.
- Typical values of defect density /1000 LOC mentioned in literature:

<table>
<thead>
<tr>
<th>Beginning Of Unit Testing</th>
<th>On Release</th>
</tr>
</thead>
<tbody>
<tr>
<td>Frequent Cited in literature</td>
<td>Highly Tested programs</td>
</tr>
<tr>
<td>16</td>
<td>2.0</td>
</tr>
</tbody>
</table>

- Long term trend: tolerable defect density limits have been gradually dropping, i.e. reliability expectations have risen.

Static and Dynamic Modeling

- Reliability at release depends on
  - Initial number of defects (parameter)
  - Effectiveness of defect removal process (parameter)
  - Operating environment
- **Static modeling**: estimate parameters before testing begins
  - Use static data like software size etc.
- **Dynamic modeling**: estimate parameters during testing
  - Record when defects are found etc.
  - Time or coverage based
What factors control defect density?

- **Need to know for**
  - static estimation of initial defect density
  - Find room for process improvement

- **Static defect density models**: The defect density is influenced by a number of factors $f_1, f_2, \ldots$ The models combine the impact of factors in two ways:
  - Additive (ex: Takahashi-Kamayachi)
    \[
    D = a_1 f_1 + a_2 f_2 + a_3 f_3 + \ldots
    \]
  - Multiplicative (ex. MIL-HDBK-217, COCOMO, RADC)
    \[
    D = C F_1(f_1) F_2(f_2) F_3(f_3) \ldots
    \]

A Static Defect Density Model

- Li, Malaiya, Denton (93, 97)
  \[
  D = C F_{ph} F_{pt} F_{mr} F_{s} F_{rv}
  \]

- $C$ is constant of proportionality, based on prior data, used for calibration.
- Default value of each function $F_i$ (submodel) is $1$.
- Each function $F_i$ is a function of some measure of the attribute.
Submodel: Phase Factor $F_{ph}$

- The table shows possible values, based on numbers reported in the literature (Musa, Gaffney, Piwowarski et al.).

<table>
<thead>
<tr>
<th>At beginning of phase</th>
<th>Multiplier</th>
</tr>
</thead>
<tbody>
<tr>
<td>Unit testing</td>
<td>4</td>
</tr>
<tr>
<td>Subsystem testing</td>
<td>2.5</td>
</tr>
<tr>
<td>System testing</td>
<td>1 (default)</td>
</tr>
<tr>
<td>Operation</td>
<td>0.35</td>
</tr>
</tbody>
</table>

- The values are given to give you an idea of variability. Actual values will depend on specific process.

Submodel: Programming Team Factor $F_{pt}$

- Based on a study by Takahashi, Kamayachi, who found that defect density declines by about 14% per year (up to seven years).

<table>
<thead>
<tr>
<th>Team's average skill level</th>
<th>Multiplier</th>
</tr>
</thead>
<tbody>
<tr>
<td>High</td>
<td>0.4</td>
</tr>
<tr>
<td>Average</td>
<td>1 (default)</td>
</tr>
<tr>
<td>Low</td>
<td>2.5</td>
</tr>
</tbody>
</table>

- It is agreed that programming team skills have a significant impact. However measuring skill is hard, there are no good quantitative studies.
SEI- Capability Maturity Model

- Software Engineering Institute Capability Maturity Model (will use CMM for SEI-CMM)
- Begun in 1986 from SEI and Mitre
  - framework for government to assess contractors
- Based on
  - Statistical quality control (Deming’s TQM, Juran)
  - Quality management (Crosby)
  - Feedback from industry and government

SEI Levels

<table>
<thead>
<tr>
<th>SEI Level</th>
<th>Key Feature</th>
<th>How many organizations?</th>
</tr>
</thead>
<tbody>
<tr>
<td>1. Initial</td>
<td>ad hoc</td>
<td>80%</td>
</tr>
<tr>
<td>2. Repeatable</td>
<td>basic management</td>
<td>15%</td>
</tr>
<tr>
<td>3. Defined</td>
<td>standardized</td>
<td>5%</td>
</tr>
<tr>
<td>4. Managed</td>
<td>quantitative control</td>
<td>4%</td>
</tr>
<tr>
<td>5. Optimizing</td>
<td>continuous improvement</td>
<td>Handful</td>
</tr>
</tbody>
</table>
Submodel: Process Maturity Factor $F_m$

- Based on Jones, Keene, Motorola data.

<table>
<thead>
<tr>
<th>SEI CMM Level</th>
<th>Multiplier</th>
</tr>
</thead>
<tbody>
<tr>
<td>Level 1</td>
<td>1.5</td>
</tr>
<tr>
<td>Level 2</td>
<td>1 (default)</td>
</tr>
<tr>
<td>Level 3</td>
<td>0.4</td>
</tr>
<tr>
<td>Level 4</td>
<td>0.1</td>
</tr>
<tr>
<td>Level 5</td>
<td>0.05</td>
</tr>
</tbody>
</table>

Submodel: Structure Factor $F_s$ (Pt 1)

- Assembly code fraction: assuming assembly has 40% more defects
  - Factor=$1+0.4 \times \text{fraction in assembly}$
  - **Complexity**: Complex modules are more fault prone, but there may be compensating factors, like people being more cautious when implementing them. No conclusive results are available that link measures like cyclomatic complexity with defect density.
- Note that by definition, defect density is defects divided by software size, which itself is a complexity metric. Question is: does adding other complexity metric help? Answer is: there is no compelling evidence.
Submodel: Structure Factor $F_s$ (Pt 2)

- **Module size**: Data from several projects suggest that very small modules have higher defect densities (Fig 1). Note that many projects have a large number of small modules (Distribution in Fig 2).

![Graph showing module size and defect density distribution](image1)


Submodel: Requirement volatility Factor $F_{ph}$

- Impact depends on degree of changes and when they occur.
- Most impact when changes occur near the end of testing.
- Malaiya & Denton: **ISSRE 99**

![Graph showing equivalent defect density over time](image2)
Using the Defect Density Model

- Calibrate submodels before use using data from a project as similar as possible.
- Constant C can range between 6-20 (Musa).
- Static models are very valuable, but high accuracy is not expected.
- Useful when dynamic test data is not yet significant.

Static Model: Example

\[ D = C \cdot F_{ph} \cdot F_{pt} \cdot F_{m} \cdot F_{s} \cdot F_{rv} \]

- For an organization, C is between 12 and 16. The team has average skills and SEI maturity level is II. About 20% of code in assembly. Other factors are average (or same as past projects).

Estimate defect density at beginning of subsystem test phase.

- Upper estimate: \( 16 \times 2.5 \times 1 \times 1 \times (1 + 0.4 \times 0.20) \times 1 = 43.2 \text{/KSLOC} \)
- Lower estimate: \( 12 \times 2.5 \times 1 \times 1 \times (1 + 0.4 \times 0.20) \times 1 = 32.4 \text{/KLOC} \)

Here the structure factor is 1 + 0.4 \times 0.20 because of some assembly code. Factor 2.5 is for the beginning of the subsystem phase.
Static Models: Limitations

- Other multiplicative models like the COCOMO cost estimation model would have similar limitations.
- The parameter values are based on past projects, which may have been somewhat different.
- Calibration will be accurate only if data from somewhat similar projects was used.
- Some factors may be statistically correlated, for example Programming team and Capability Maturity factors.
- Still such models can be very useful at the beginning of projects for planning the test effort.